

Notice of References Cited	Application/Control No. 10/615,021	Applicant(s)/Patent Under Reexamination CHANG, WON-KIL	
	Examiner Shih-wen Hsieh	Art Unit 2861	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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FOREIGN PATENT DOCUMENTS

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